

**9NM65Z**

Preliminary

Power MOSFET

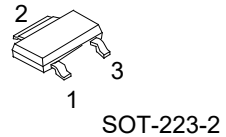
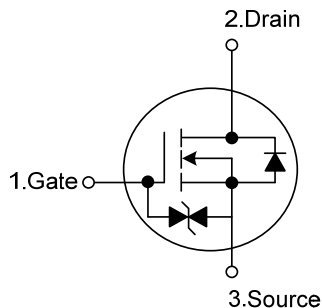
**9.0A, 650V N-CHANNEL
SUPER-JUNCTION MOSFET****DESCRIPTION**

The UTC **9NM65Z** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at AC-DC converters for power applications.

FEATURES

* $R_{DS(ON)} \leq 1.1 \Omega$ @ $V_{GS}=10V$, $I_D=4.5A$

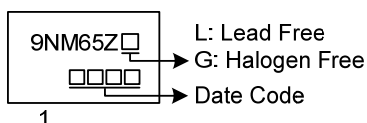
* High Switching Speed

SYMBOL**ORDERING INFORMATION**

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
9NM65ZL-AA2-R	9NM65ZG-AA2-R	SOT-223-2	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

9NM65ZG-AA2-R	(1) Packing Type	(1) R: Tape Reel
	(2) Package Type	(2) AA2: SOT-223-2
	(3) Green Package	(3) G: Halogen Free and Lead Free, L: Lead Free

MARKING

■ ABSOLUTE MAXIMUM RATINGS ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	650	V
Gate-Source Voltage		V_{GSS}	± 20	V
Drain Current	Continuous	I_D	9	A
	Pulsed (Note 2)	I_{DM}	18	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	66	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2.3	V/ns
Power Dissipation		P_D	16	W
Junction Temperature		T_J	+150	$^{\circ}\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L = 30\text{mH}$, $I_{AS} = 2.1\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\ \Omega$ Starting $T_J = 25^{\circ}\text{C}$

4. $I_{SD} \leq 9.0\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	150	$^{\circ}\text{C}/\text{W}$
Junction to Case	θ_{JC}	7.81	$^{\circ}\text{C}/\text{W}$

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

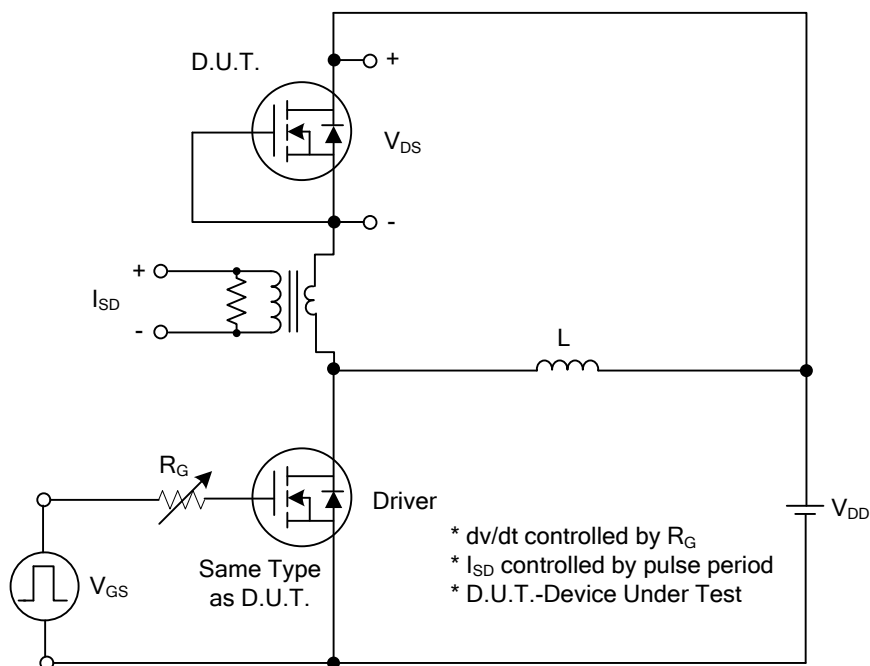
■ ELECTRICAL CHARACTERISTICS ($T_J=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	V _{GS} =0V, I _D = 250μA	650			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} =650V, V _{GS} =0V			10	μA
Gate-Source Leakage Current	Forward	I _{GSS}	V _{GS} =20V, V _{DS} =0V			10	μA
	Reverse		V _{GS} =-20V, V _{DS} =0V			-10	μA
ON CHARACTERISTICS							
Gate Threshold Voltage		V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	2.5		4.5	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =4.5A			1.1	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C _{ISS}	V _{GS} =0V, V _{DS} =50V f=1.0 MHz		400		pF
Output Capacitance		C _{OSS}			39		pF
Reverse Transfer Capacitance		C _{RSS}			5.5		pF
SWITCHING CHARACTERISTICS							
Total Gate Charge (Note 1)		Q _G	V _{DS} =520V, V _{GS} =10V, I _D =9.0A (Note 1, 2)		17.2		nC
Gateource Charge		Q _{GS}			5.6		nC
Gate-Drain Charge		Q _{GD}			3.3		nC
Turn-on Delay Time (Note 1)		t _{D(ON)}	V _{DS} =100V, V _{GS} =10V, I _D =9.0A, R _G =25Ω (Note 1, 2)		6		ns
Rise Time		t _R			18		ns
Turn-off Delay Time		t _{D(OFF)}			60		ns
Fall-Time		t _F			68		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I _S				9	A
Maximum Body-Diode Pulsed Current		I _{SM}				18	A
Drain-Source Diode Forward Voltage (Note 1)		V _{SD}	I _S =9.0A, V _{GS} =0V			1.4	V
Reverse Recovery Time (Note 1)		t _{rr}	I _S =9.0A, V _{GS} =0V		315		ns
Reverse Recovery Charge		Q _{rr}	dl _F /dt=100A/μs (Note1)		3.2		μC

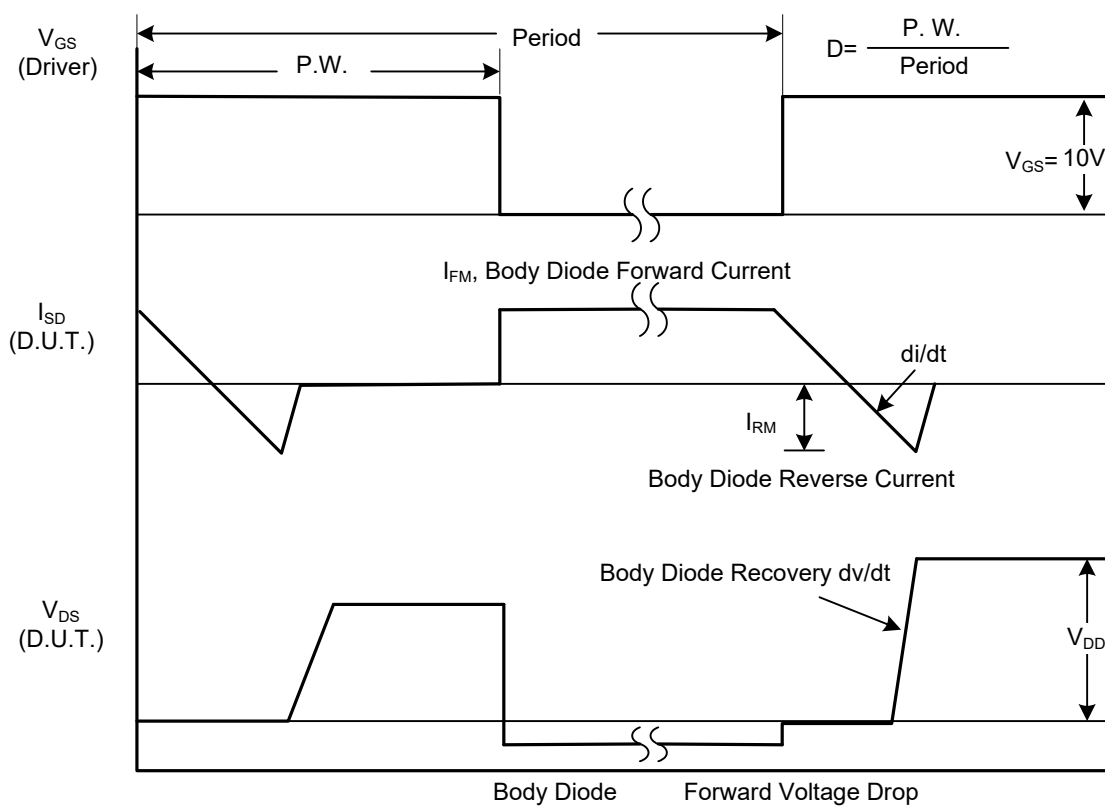
Notes: 1. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

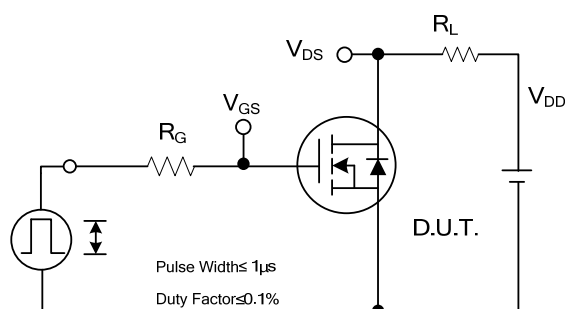


Peak Diode Recovery dv/dt Test Circuit

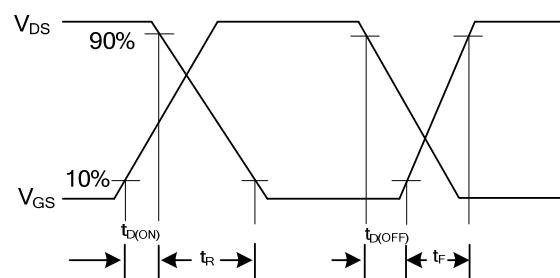


Peak Diode Recovery dv/dt Waveforms

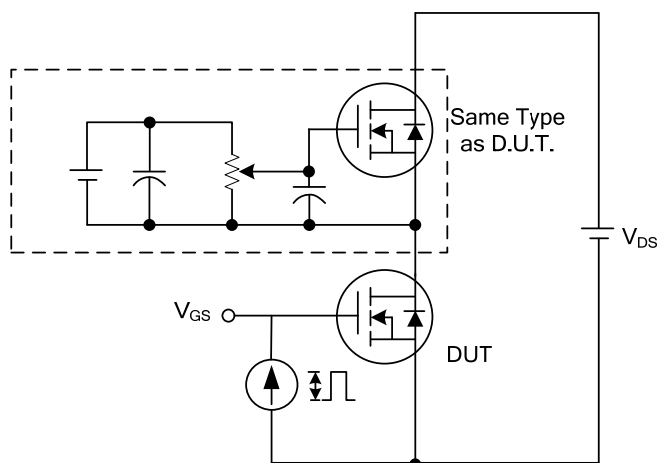
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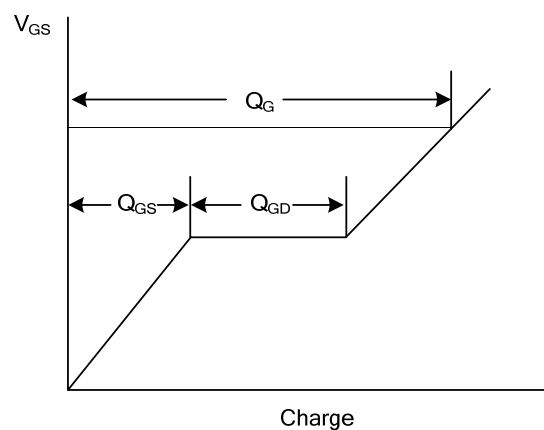
Switching Test Circuit



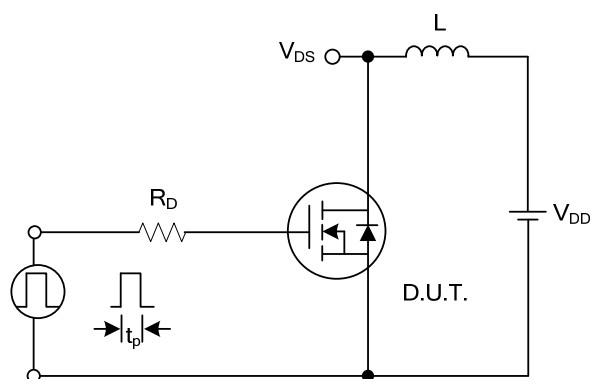
Switching Waveforms



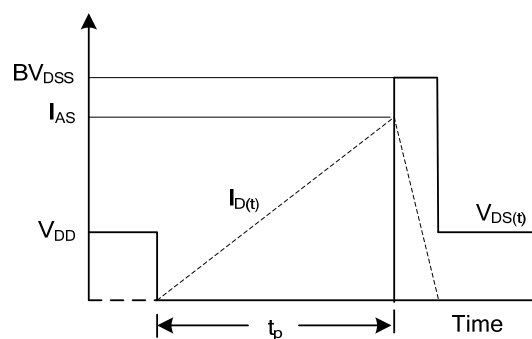
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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